

Notice of References Cited

Application/Control No.

10/541,689

Applicant(s)/Patent Under
Reexamination
ANNIC, ETIENNE

Examiner

SHIH-WEI KRAFT

Art Unit

2194

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0111963 A1	08-2002	Gebert et al.	707/513
*	B	US-6,654,754 B1	11-2003	Knauff et al.	1/1
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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